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
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- ☐ **1. The MSFC Image Data Processing System**  
Wilson, R.M.; Teuber, D.L.; Thomas, D.T.; Watkins, J.R.; Cooper, C.M.;  
[Computer](#)  
Volume 10, [Issue 8](#), Aug. 1977 Page(s):37 - 44  
Digital Object Identifier 10.1109/C-M.1977.217821  
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## 2. Image quality analysis for dual energy subtraction imaging with a femtosecond laser-based hard X-ray source

Ichalalene, Z.; Jiang, Z.; Kieffer, J.C.; Dorchies, F.; Krol, A.; Chamberlain, C.C.;

Selected Topics in Quantum Electronics, IEEE Journal of

Volume 7, Issue 6, Nov.-Dec. 2001 Page(s):912 - 917

Digital Object Identifier 10.1109/2944.983293

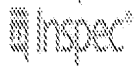
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